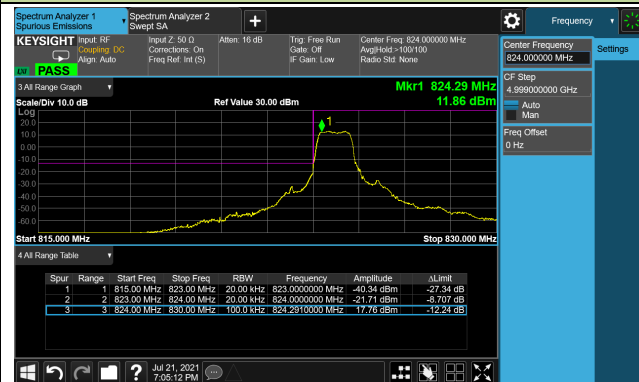
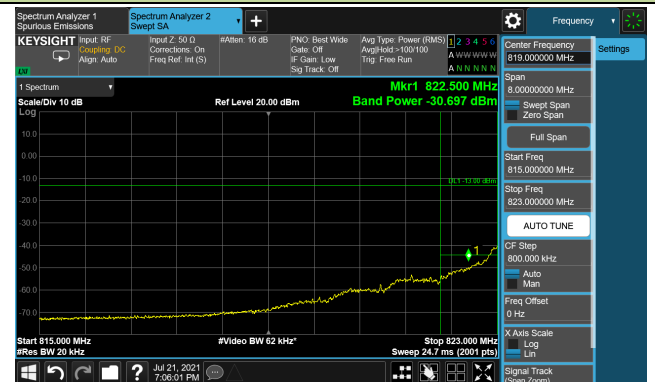


1.4MHz Channel Bandwidth - Full RB

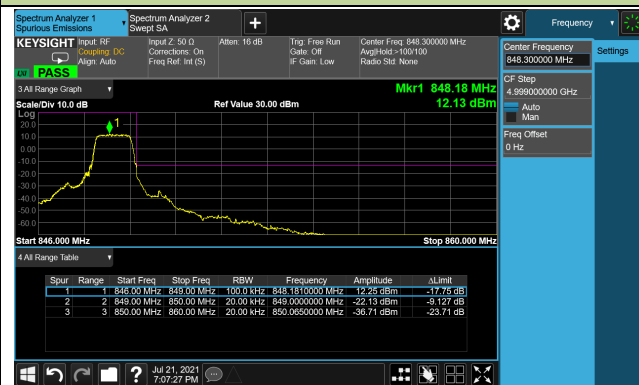
Lower Band Edge



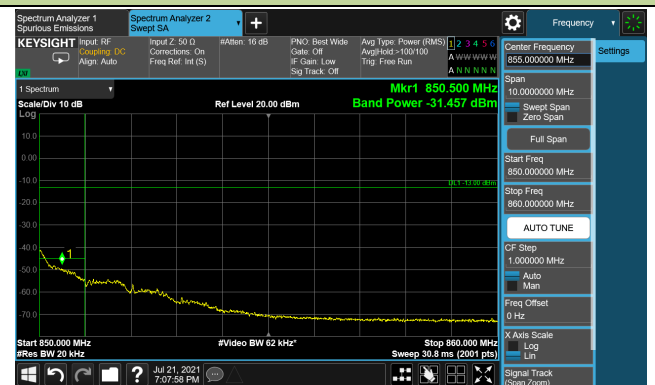
Lower Extended Band Edge



Upper Band Edge

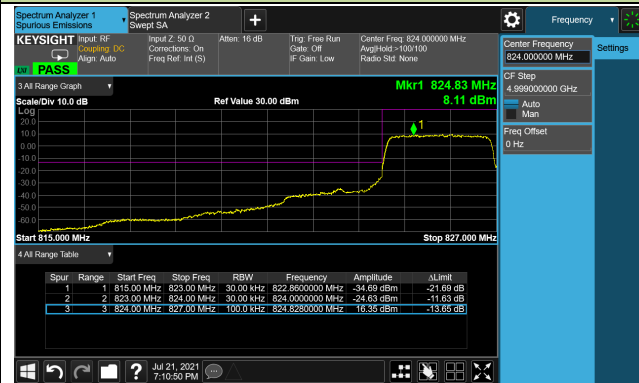


Upper Extended Band Edge

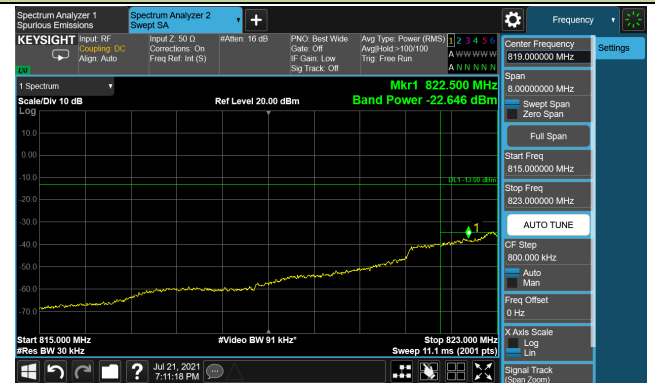


3MHz Channel Bandwidth - Full RB

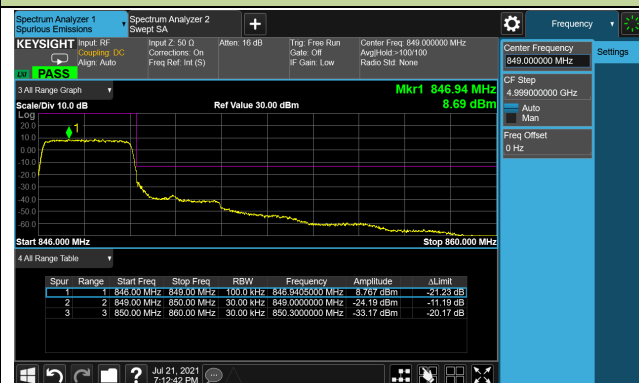
Lower Band Edge



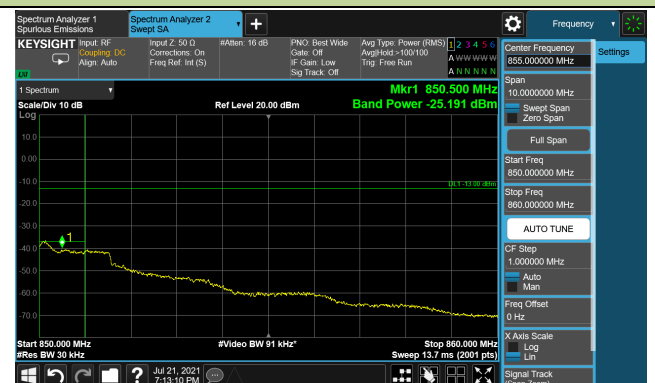
Lower Extended Band Edge



Upper Band Edge

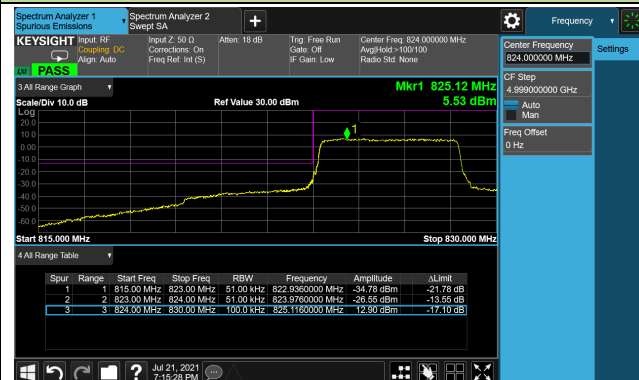


Upper Extended Band Edge

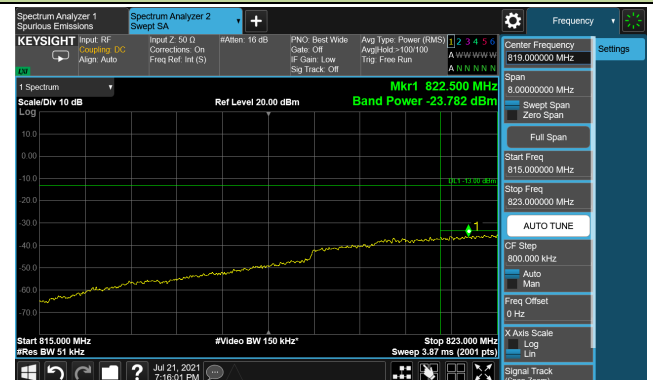


5MHz Channel Bandwidth - Full RB

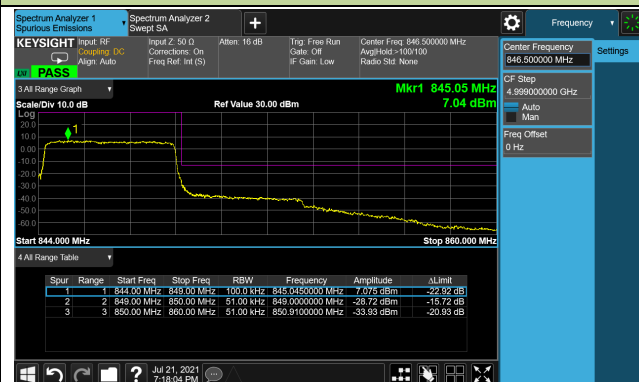
Lower Band Edge



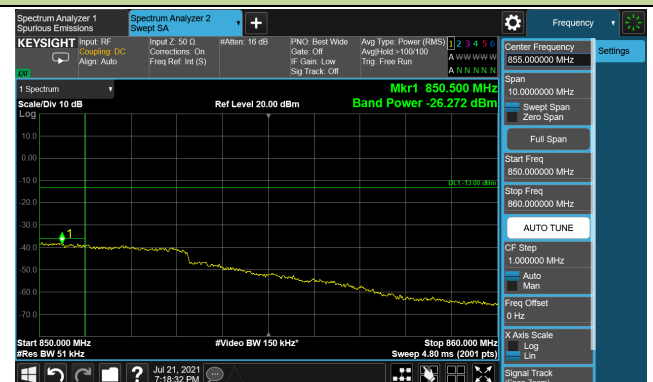
Lower Extended Band Edge



Upper Band Edge

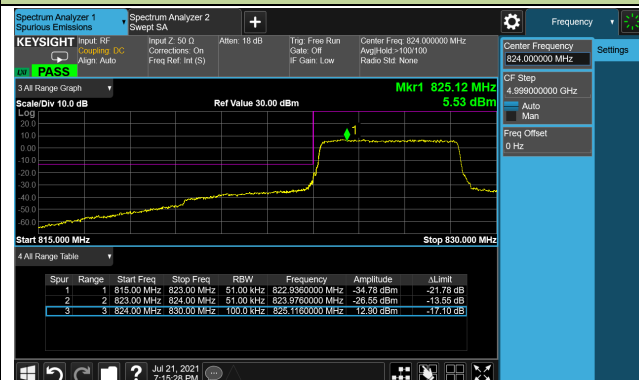


Upper Extended Band Edge

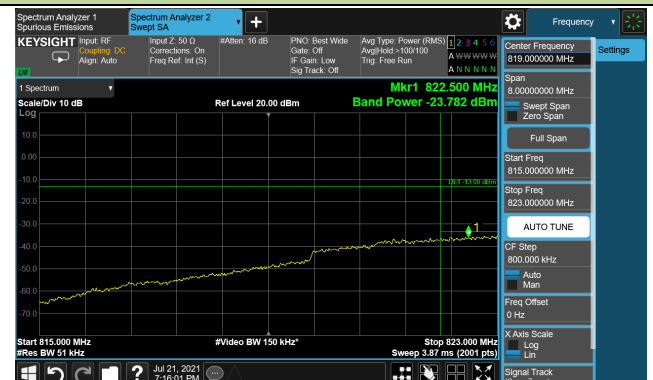


10MHz Channel Bandwidth - Full RB

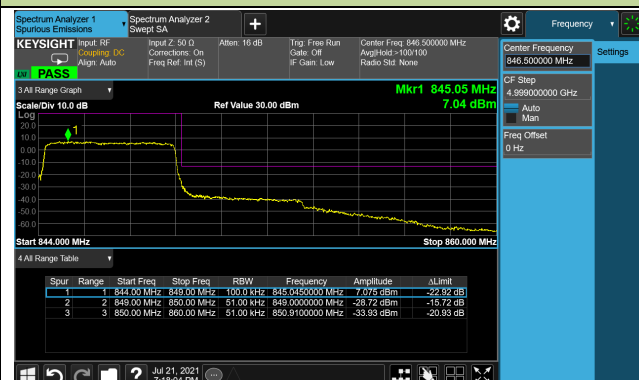
Lower Band Edge



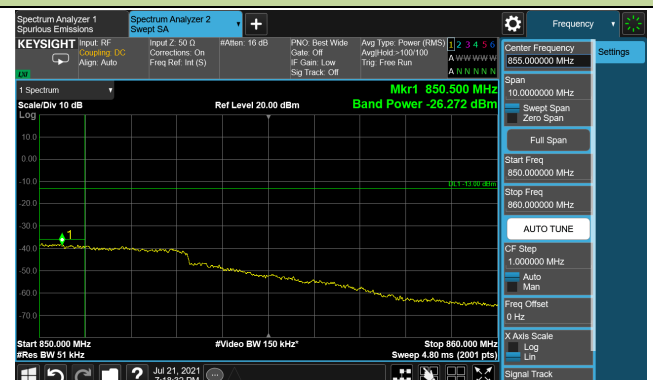
Lower Extended Band Edge



Upper Band Edge



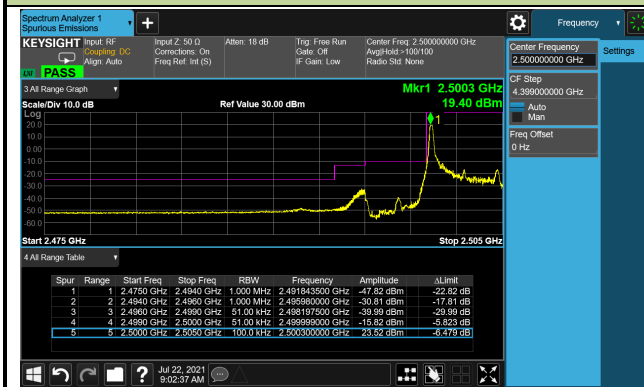
Upper Extended Band Edge



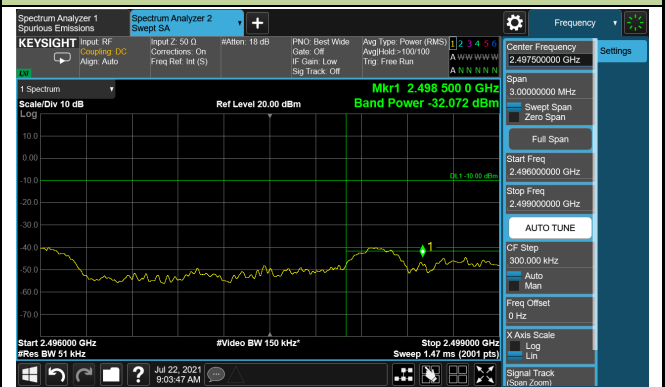
Product	LTE Module	Test Site	SIP-SR1
Test Engineer	Candy Luo	Test Date	2021/07/22
Test Band	LTE Band 7		

5MHz Channel Bandwidth - 1RB

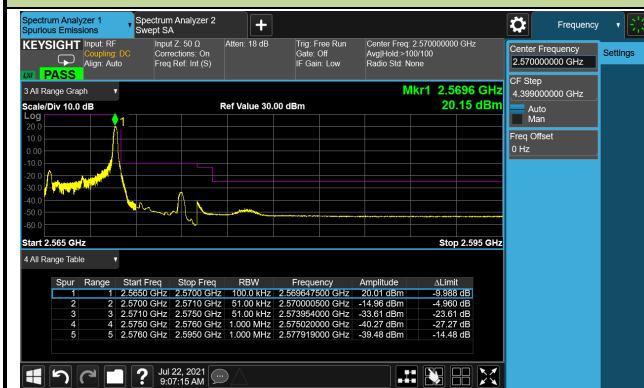
Lower Band Edge



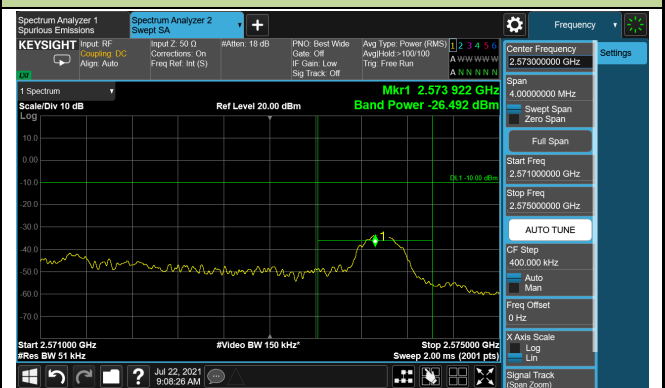
Lower Extended Band Edge



Upper Band Edge

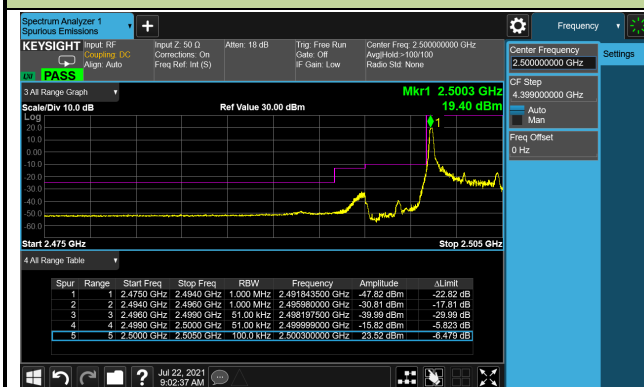


Upper Extended Band Edge

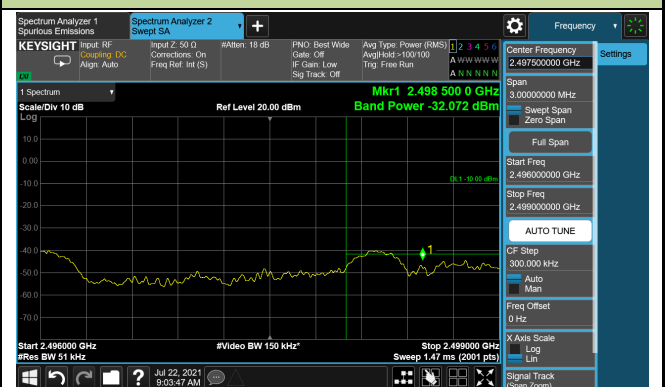


10MHz Channel Bandwidth - 1RB

Lower Band Edge



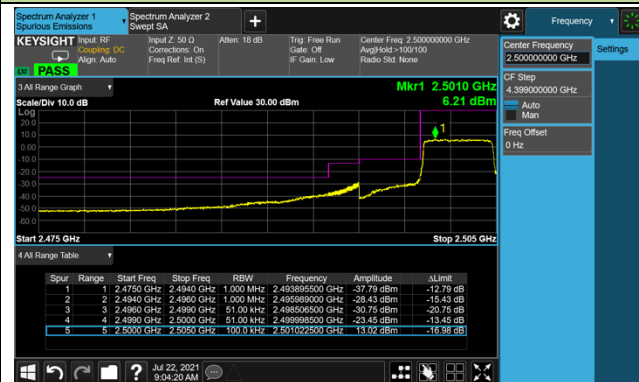
Lower Extended Band Edge



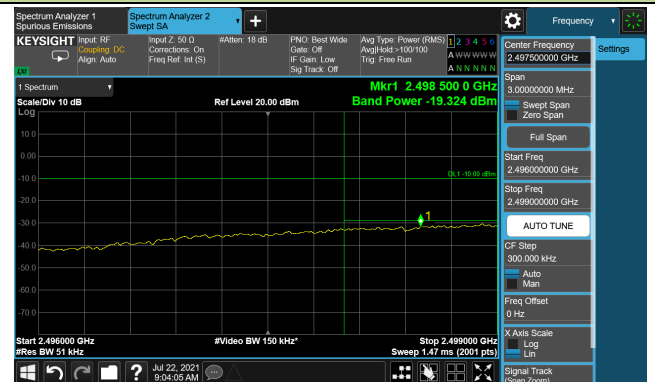


5MHz Channel Bandwidth - Full RB

Lower Band Edge

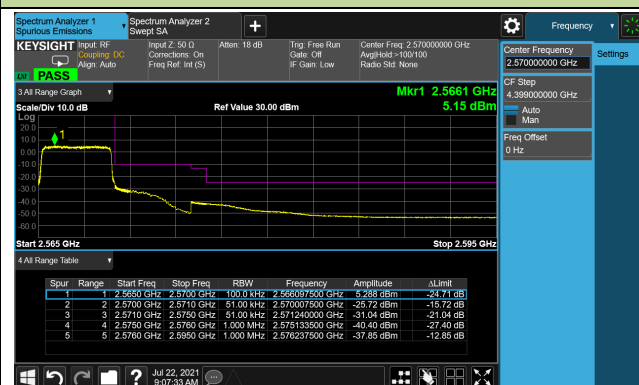


Upper Band Edge

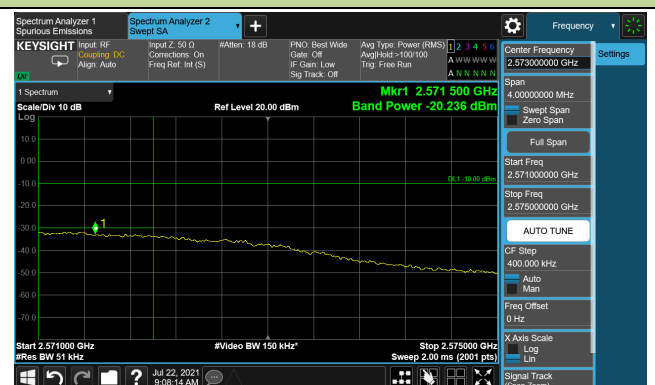


10MHz Channel Bandwidth - Full RB

Lower Band Edge

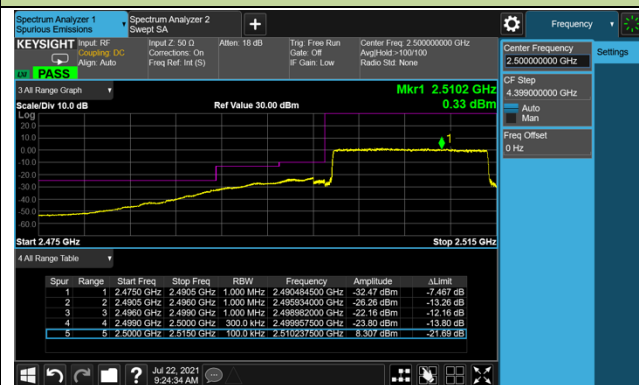


Upper Band Edge

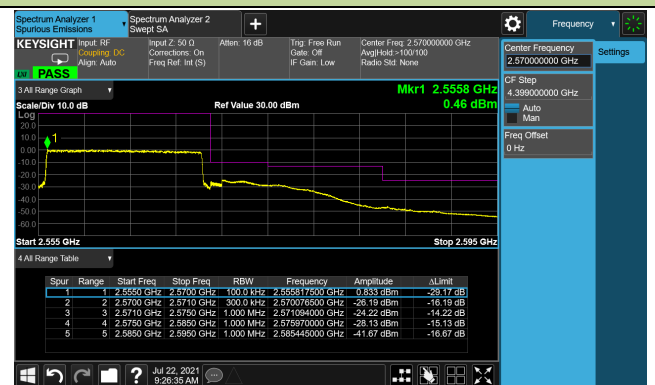


15MHz Channel Bandwidth - Full RB

Lower Band Edge

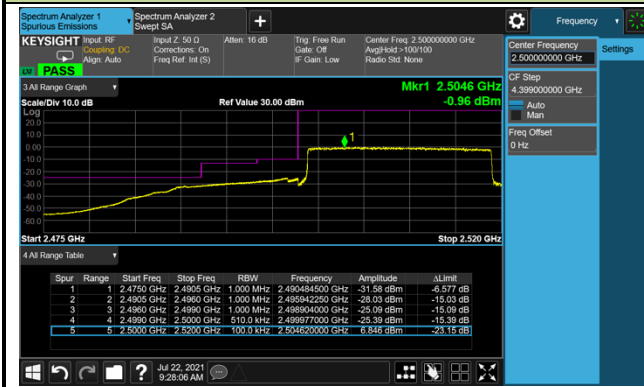


Upper Band Edge

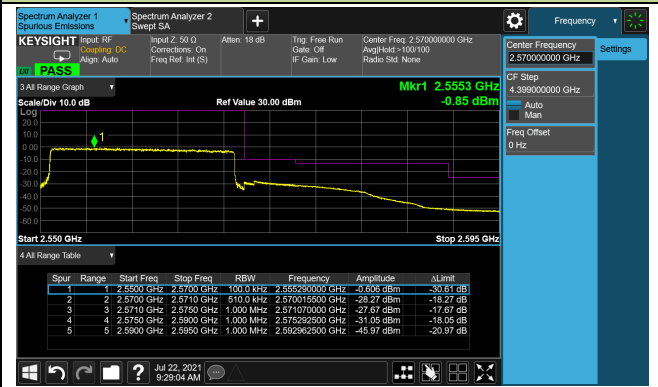


20MHz Channel Bandwidth - Full RB

Lower Band Edge



Upper Band Edge



5.6. Peak to Average Ratio Measurement

5.6.1. Test Limit

A peak to average ratio measurement is performed at the conducted port of the EUT. The spectrum analyzers Complementary Cumulative Distribution Function (CCDF) measurement profile is used to determine the largest deviation between the average and the peak power of the EUT in a given bandwidth. The CCDF curve shows how much time the peak waveform spends at or above a given average power level. The percent of time the signal spends at or above the level defines the probability for that particular power level.

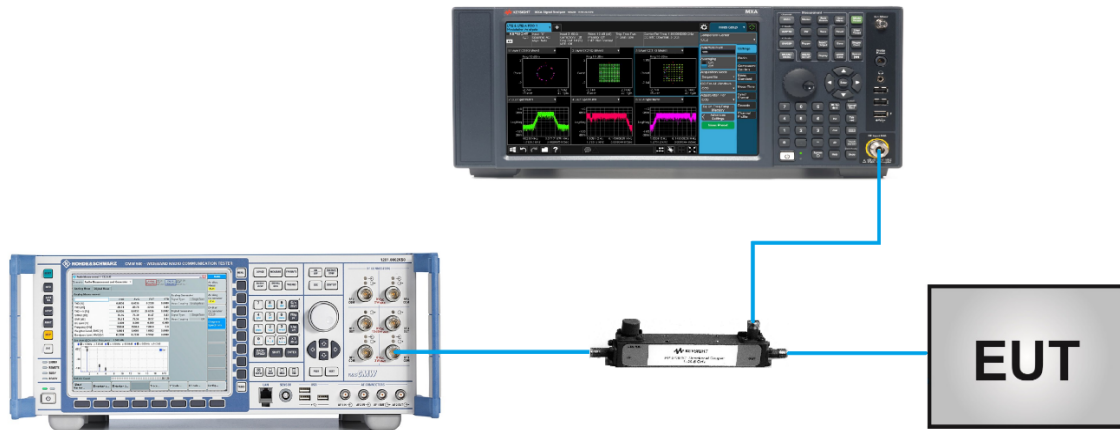
5.6.2. Test Procedure

ANSI C63.26-2015 - Section 5.2.3.4 (CCDF).

5.6.3. Test Setting

1. Set the resolution / measurement bandwidth $\geq$ signal's occupied bandwidth
2. Set the number of counts to a value that stabilizes the measured CCDF curve
3. Record the maximum PARR level associated with a probability of 0.1%

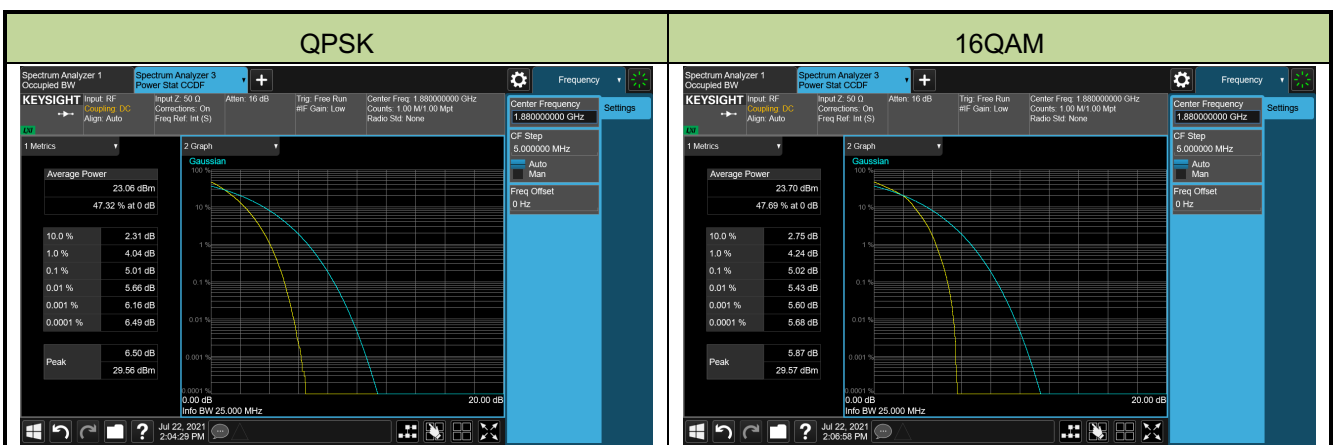
5.6.4. Test Setup



5.6.5. Test Result

Product	LTE Module	Test Site	SIP-SR1
Test Engineer	Candy Luo	Test Date	2021/07/22
Test Band	Band 2		

Channel No.	Frequency (MHz)	Channel Bandwidth (MHz)	Peak to Average Ratio (dB)	Limit (dB)	Result
QPSK					
18900	1880.0	20	5.01	≤ 13.00	Pass
16QAM					
18900	1880.0	20	5.02	≤ 13.00	Pass



Product	LTE Module	Test Site	SIP-SR1
Test Engineer	Candy Luo	Test Date	2021/07/22
Test Band	Band 4/66		

Channel No.	Frequency (MHz)	Channel Bandwidth (MHz)	Peak to Average Ratio (dB)	Limit (dB)	Result
QPSK					
132322	1745.0	20	5.39	≤ 13.00	Pass
16QAM					
132322	1745.0	20	5.47	≤ 13.00	Pass

